

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE PATENT APPLICATION OF: OKUBO et al.
SERIAL NO.: 10/544,178
ATTORNEY DOCKET NO.: 061063-0317066
FILING DATE: April 24, 2006
CONFIRMATION NO.: 8571
ART UNIT: 2826
EXAMINER: WHITNEY MOORE
FOR: METHOD FOR INSPECTION, PROCESS FOR MAKING ANALYTIC PIECE,
METHOD FOR ANALYSIS, ANALYZER, PROCESS FOR PRODUCING SOI
WAFER, AND SOI WAFER

COMMENTS ON EXAMINER'S STATEMENT OF REASONS FOR ALLOWANCE

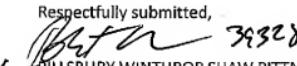
Mail Stop Issue Fee
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In reply to the Notice of Allowability dated October 19, 2009, consideration of the following comments are respectfully requested.

Applicant respectfully submits that the subject matter of the allowed claims are patentable for their respective recitations of claimed combinations as a whole, without any particular criticality or distinguishing feature being attributable to any one or more of such features, and without any narrowing interpretation being imposed on any of such features. The Applicant respectfully submits that the dependent claims are allowable not only for their dependence on the allowed independent claims, but also for the additional subject matter recited in each of those dependent claims.

Respectfully submitted,


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Date: January 15, 2010
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